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April 2016

FQD18N20V2

N-Channel QFET® MOSFET 200 V, 15 A, 140 mΩ

Description

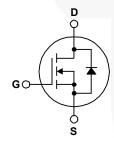
This N-Channel enhancement mode power MOSFET is • 15 A, 200 V, $R_{DS(on)}$ = 140 m Ω (Max.) @ V_{GS} = 10 V, produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state

• Low Gate Charge (Typ. 20 nC) resistance, and to provide superior switching performance • Low Crss (Typ. 25 pF) and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power • 100% Avalanche Tested factor correction (PFC), and electronic lamp ballasts.

Features

- $I_D = 7.5 A$





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQD18N20V2TM	Unit
V_{DSS}	Drain-Source Voltage		200	V
I _D	Drain Current - Continuous (T _C = 25°C)		15	Α
	- Continuous (T _C = 100°C)		9.75	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	60	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	340	mJ
I _{AR}	Avalanche Current	(Note 1)	15	Α
E _{AR}	Repetitive Avalanche Energy (Note 1)		8.3	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		6.5	V/ns
P _D	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		83	W
	- Derate above 25°C		0.67	W/°C
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum Lead Lemperature for Loldering, 1/8" from Case for 5 Seconds.		300	°C

Thermal Characteristics

Symbol	Parameter	FQD18N20V2TM	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	1.5	
В	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.	110	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (*1 in ² Pad of 2-oz Copper), Max.	50	

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQD18N20V2TM	DV218N20	DPAK	Tape and Reel	330 mm	16 mm	2500 units

Electrical Characteristics

T_C = 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	200			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.25		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 200 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 160 V, T _C = 125°C		-	10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 7.5 A		0.12	0.14	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 7.5 A		11		S
	ic Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		830	1080	pF
Coss	Output Capacitance	f = 1.0 MHz		200	260	pF
C _{rss}	Reverse Transfer Capacitance			25	33	pF
C _{oss}	Output Capacitance	V _{DS} = 160 V, V _{GS} = 0 V, f = 1.0 MHz		70		pF
C _{oss} eff.	Effective Output Capacitance	V_{DS} = 0V to 160 V, V_{GS} = 0 V		135		pF
Switchi	ing Characteristics					
$t_{d(on)}$	Turn-On Delay Time	V _{DD} = 100 V, I _D = 18 A,		16	40	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		133	275	ns
t _{d(off)}	Turn-Off Delay Time			38	85	ns
t _f	Turn-Off Fall Time	(Note 4)	/	62	135	ns
Qg	Total Gate Charge	V _{DS} = 160 V, I _D = 18 A,		20	26	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		5.6	/	nC
Q _{gd}	Gate-Drain Charge	(Note 4)		10		nC
R _G	Gate Resistance	f= 1MHz	0.5		2.5	Ω

Drain-Source Diode Characteristics and Maximum Ratings

I_S	Maximum Continuous Drain-Source Diode Forward Current				15	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current			-	60	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 15 A			1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 18 A,		158		ns
Q _{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs		1.0		μС

- Notes: 1. Repetitive rating : pulse-width limited by maximum junction temperature. 2. L = 1.58 mH, I_{AS} = 18 A, V_{DD} = 50 V, R_G = 25 Ω , starting T_J = 25°C. 3. I_{SD} \leq 18 A, di/dt \leq 200 A/µs, V_{DD} \leq BV_{DSS}, starting T_J = 25°C. 4. Essentially independent of operating temperature.

Typical Characteristics

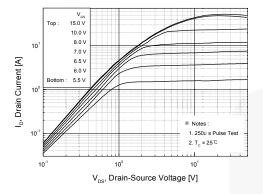


Figure 1. On-Region Characteristics

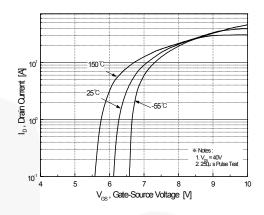


Figure 2. Transfer Characteristics

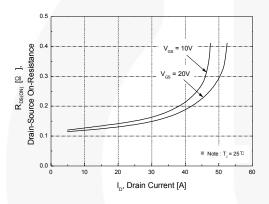


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

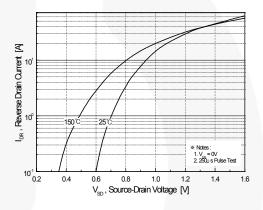


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

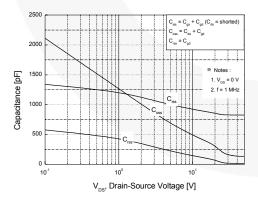


Figure 5. Capacitance Characteristics

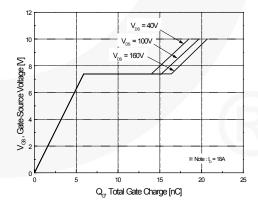
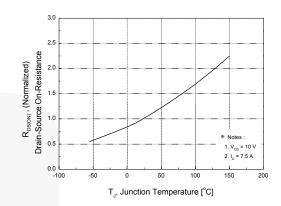


Figure 6. Gate Charge Characteristics

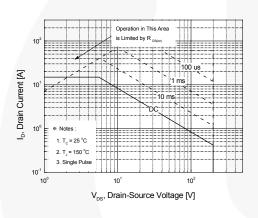
1.2 Drain-Source Breakdown Voltage BV _{DSS} , (Normalized) 1. V_{GS} = 0 V 2. I_D = 250 µ A -100 150 T,, Junction Temperature [°C] Figure 7. Breakdown Voltage Variation

Typical Characteristics (Continued)



vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



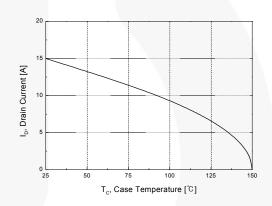


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

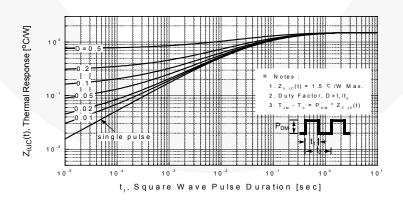


Figure 11. Transient Thermal Response Curve

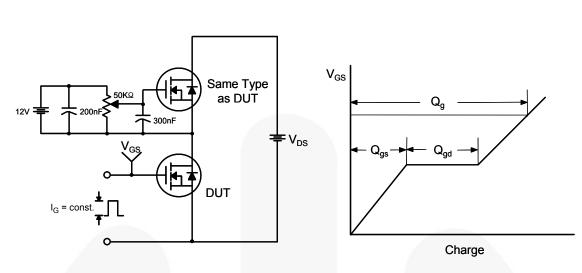


Figure 12. Gate Charge Test Circuit & Waveform

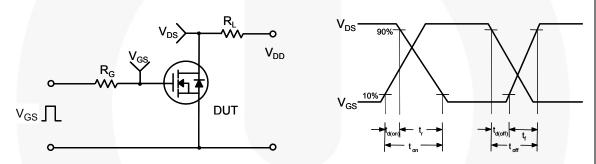


Figure 13. Resistive Switching Test Circuit & Waveforms

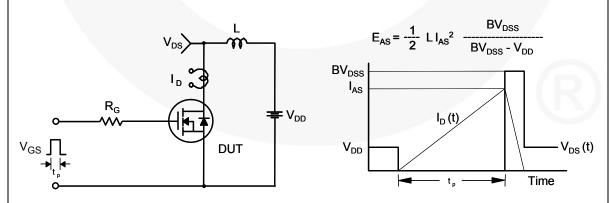
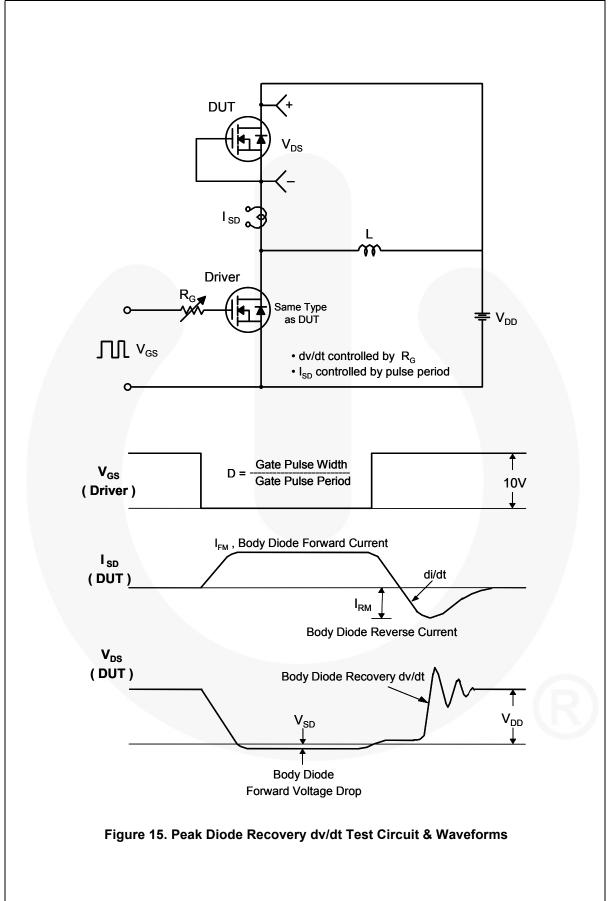
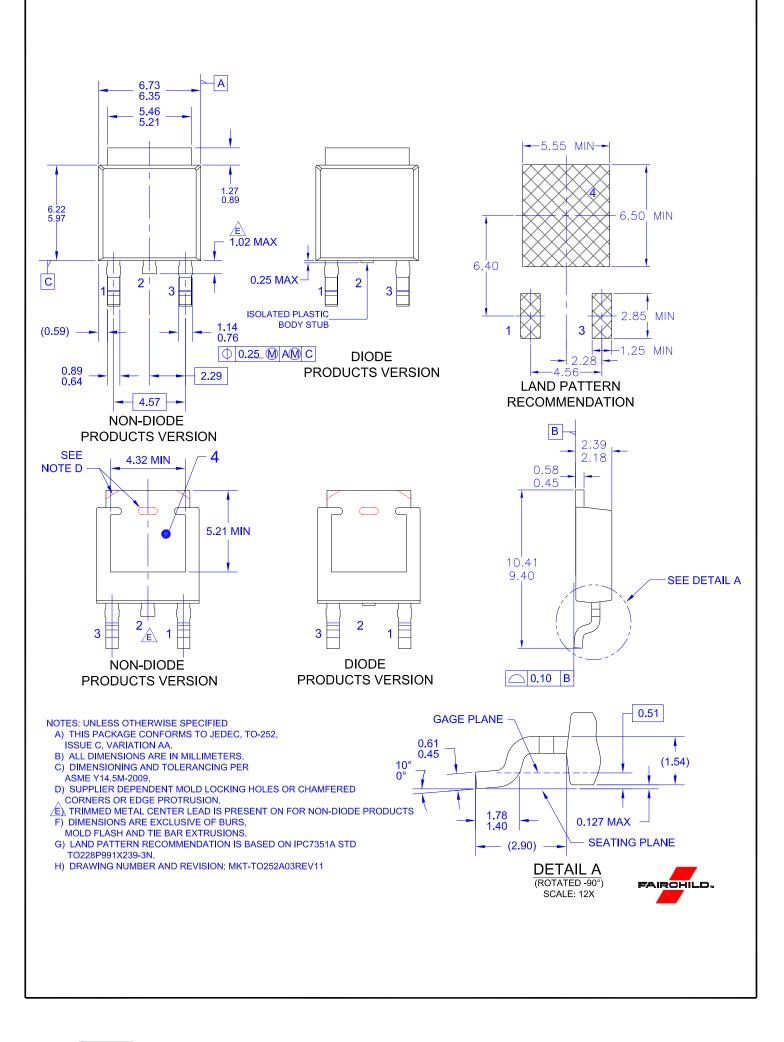


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms





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